

<b>Notice of References Cited</b>	Application/Control No. 10/800,826	Applicant(s)/Patent Under Reexamination WON ET AL.	
	Examiner David E. Graybill	Art Unit 2822	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,852,307 A	12-1998	Aoyama et al.	257/295
*	B	US-6,078,072 A	06-2000	Okudaira et al.	257/295
*	C	US-6,156,599 A	12-2000	Aoyama et al.	438/238
*	D	US-6,187,622 B1	02-2001	Kuroiwa et al.	438/240
*	E	US-2001/0006838 A1	07-2001	Won et al.	438/396
*	F	US-2001/0050391 A1	12-2001	MATSUNO et al.	257/306
*	G	US-6,333,529 B1	12-2001	Ashida et al.	257/295
*	H	US-6,403,441 B1	06-2002	Takehiro et al.	438/396
*	I	US-6,420,582 B1	07-2002	Okamoto, Koji	556/136
*	J	US-2002/0192896 A1	12-2002	Matsui et al.	438/239
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O	JP 11168200 A	06-1999	Japan	OKUDAIRA et al.	H01L 27/108
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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